Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/652,138	TANAKA, KOICHIRO		
Examiner	Art Unit		
Zohreh A. Fay	1618		

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
The parent application was reviewed	8/30/2006	Z.F .
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